

## CLAIMS

1. A semiconductor device comprising:
  - a plurality of memory blocks each having memory cells;
  - a plurality of redundancy units for replacement of defective memory cells in the plurality of memory blocks; and
  - a plurality of storage circuits each configured to store a defective address assigned to a defective memory cell in the plurality of memory blocks, and also store mapping information indicative of a relationship with the redundancy units;wherein the number of the storage circuits is smaller than the number of the redundancy units.